







**TMUX6236** SCDS449A - APRIL 2022 - REVISED JULY 2022

# TMUX6236 36 V, Low-RON, 2:1 (SPDT), 2-Channel Precision Switch With 1.8 V Logic

#### 1 Features

Dual supply range: ±4.5 V to ±18 V Single supply range: 4.5 V to 36 V

Low on-resistance: 2 Ω

High current support: 330 mA (maximum) (WQFN)

-40°C to +125°C operating temperature

1.8 V logic compatible

Integrated pull-down resistor on logic pins

Fail-safe logic

Rail-to-rail operation

**Bidirectional operation** 

## 2 Applications

Factory automation and industrial controls

Programmable logic controllers (PLC)

Analog input modules

ATE test equipment

Battery monitoring systems

Ultrasound scanners

Patient monitoring and diagnostics

Optical networking

Optical test equipment

Remote radio units

Wired networking

Data acquisition systems

### 3 Description

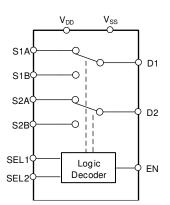
The TMUX6236 is a complementary metal-oxide semiconductor (CMOS) switch with two 2:1 switches. The device works well with dual supplies (±4.5 V to ±18 V), a single supply (4.5 V to 36 V), or asymmetric supplies (such as  $V_{DD}$  = 12 V,  $V_{SS}$  = -5 V). The TMUX6236 supports bidirectional analog and digital signals on the source (Sx) and drain (D) pins ranging from  $V_{SS}$  to  $V_{DD}$ .

All logic control inputs support logic levels from 1.8 V to V<sub>DD</sub>, ensuring both TTL and CMOS logic compatibility when operating in the valid supply voltage range. Fail-Safe Logic circuitry allows voltages on the control pins to be applied before the supply pin, protecting the device from potential damage.

#### Device Information<sup>(1)</sup>

PART NUMBER	PACKAGE	BODY SIZE (NOM)		
TMUX6236	WQFN (16) (RUM)	4.00 mm × 4.00 mm		

For all available packages, see the package option addendum at the end of the data sheet.



**Block Diagram** 



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# **4 Revision History**

С	hanges from Revision * (April 2022) to Revision A (July 2022)	Page
•	Changed the status of the data sheet from: Advanced Information to: Production Data	



# **5 Pin Configuration and Functions**

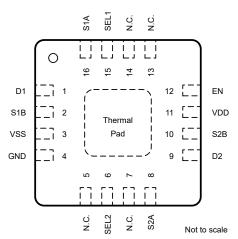


Figure 5-1. RUM Package, 16-Pin WQFN (Top View)

Table 5-1. Pin Functions

	PIN	TYPE(1)	DESCRIPTION	
NAME	NO.	I TPE(")	DESCRIPTION	
D1	1	I/O	Drain pin. Can be an input or output.	
D2	9	I/O	Drain pin. Can be an input or output.	
EN	12	I	Active high logic enable, has internal pull-up resistor. When this pin is low, all switches are turned off. When this pin is high, the SEL logic input determine which switch is turned on.	
GND	4	Р	Ground (0 V) reference	
NC	5, 7, 13, 14	_	No internal connection. Can be shorted to GND or left floating.	
S1A	16	I/O	Source pin 1A. Can be an input or output.	
S1B	2	I/O	Source pin 1B. Can be an input or output.	
S2A	8	I/O	Source pin 2A. Can be an input or output.	
S2B	10	I/O	Source pin 2B. Can be an input or output.	
SEL1	15	1	Logic control input, has internal pull-down resistor. Table 8-1 lists how to control the switch connection.	
SEL2	6	I	Logic control input, has internal pull-down resistor. Table 8-1 lists how to control the switch connection.	
V <sub>DD</sub>	11	Р	Positive power supply. This pin is the most positive power-supply potential. For reliable operation, connect a decoupling capacitor ranging from 0.1 $\mu$ F to 10 $\mu$ F between V <sub>DD</sub> and GND.	
		Negative power supply. This pin is the most negative power-supply potential. In single-supply applications, this pin can be connected to ground. For reliable operation, connect a decoupling capacitor ranging from 0.1 $\mu$ F to 10 $\mu$ F between V <sub>SS</sub> and GND.		
Thermal Pad —		_	The thermal pad is not connected internally. There is no requirement to electrically connect this pad. If connected, however, it is recommended that the pad be left floating or tied to GND.	

(1) I = input, O = output, P = power



## **6 Specifications**

## **6.1 Absolute Maximum Ratings**

over operating free-air temperature range (unless otherwise noted)(1) (2)

		MIN	MAX	UNIT
V <sub>DD</sub> – V <sub>SS</sub>			38	V
V <sub>DD</sub>	Supply voltage	-0.5	38	V
V <sub>SS</sub>		-38	0.5	V
V <sub>SEL</sub> or V <sub>EN</sub>	Logic control input pin voltage (SELx)	-0.5	38	V
I <sub>SEL</sub> or I <sub>EN</sub>	Logic control input pin current (SELx)	-30	30	mA
V <sub>S</sub> or V <sub>D</sub>	Source or drain voltage (Sx, Dx)	V <sub>SS</sub> -0.5	V <sub>DD</sub> +0.5	V
I <sub>IK</sub>	Diode clamp current <sup>(3)</sup>	-30	30	mA
I <sub>S</sub> or I <sub>D (CONT)</sub>	Source or drain continuous current (Sx, Dx)		I <sub>DC</sub> + 10 % <sup>(4)</sup>	mA
T <sub>A</sub>	Ambient temperature	-55	150	°C
T <sub>stg</sub>	Storage temperature	-65	150	°C
TJ	Junction temperature		150	°C
P <sub>tot</sub>	Total power dissipation (QFN) <sup>(5)</sup>		1650	mW

- (1) Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.
- 2) All voltages are with respect to ground, unless otherwise specified.
- (3) Pins are diode-clamped to the power-supply rails. Over voltage signals must be voltage and current limited to maximum ratings.
- 4) Refer to Source or Drain Continuous Current table for IDC specifications.
- (5) For QFN package:  $P_{tot}$  derates linearly above  $T_A = 70^{\circ}$ C by 24.2mW/°C.

### 6.2 ESD Ratings

			VALUE	UNIT
V <sub>(ESD)</sub> Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/ JEDEC JS-001, all pins <sup>(1)</sup>	±1000	\/	
V <sub>(ESD)</sub>	Electrostatic discharge	Charged device model (CDM), per ANSI/ESDA/ JEDEC JS-002, all pins <sup>(2)</sup>	±500	V

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

#### **6.3 Thermal Information**

		TMUX6236	
	THERMAL METRIC <sup>(1)</sup>	RUM (WQFN)	UNIT
		16 PINS	
R <sub>θJA</sub>	Junction-to-ambient thermal resistance	41.5	°C/W
R <sub>0JC(top)</sub>	Junction-to-case (top) thermal resistance	25.1	°C/W
R <sub>0JB</sub>	Junction-to-board thermal resistance	16.5	°C/W
$\Psi_{JT}$	Junction-to-top characterization parameter	0.3	°C/W
$\Psi_{JB}$	Junction-to-board characterization parameter	16.4	°C/W
R <sub>0JC(bot)</sub>	Junction-to-case (bottom) thermal resistance	2.9	°C/W

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

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## **6.4 Recommended Operating Conditions**

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
V <sub>DD</sub> – V <sub>SS</sub> (1)	Power supply voltage differential	4.5	36	V
$V_{DD}$	Positive power supply voltage	4.5	36	V
V <sub>S</sub> or V <sub>D</sub>	Signal path input/output voltage (source or drain pin) (Sx, D)	V <sub>SS</sub>	$V_{DD}$	V
V <sub>SEL</sub> or V <sub>EN</sub>	Address or enable pin voltage	0	36	V
I <sub>S</sub> or I <sub>D (CONT)</sub>	Source or drain continuous current (Sx, D)		I <sub>DC</sub> <sup>(2)</sup>	mA
T <sub>A</sub>	Ambient temperature	-40	125	°C

- $V_{DD}$  and  $V_{SS}$  can be any value as long as 4.5 V  $\leq$  ( $V_{DD} V_{SS}$ )  $\leq$  36 V, and the minimum  $V_{DD}$  is met. Refer to *Source or Drain Continuous Current* table for  $I_{DC}$  specifications.

### 6.5 Source or Drain Continuous Current

at supply voltage of  $V_{DD}$  ± 10%,  $V_{SS}$  ± 10 % (unless otherwise noted)

CONTINU	CONTINUOUS CURRENT PER CHANNEL (I <sub>DC</sub> ) (2)		T <sub>A</sub> = 85°C	T <sub>Δ</sub> = 125°C	UNIT
PACKAGE	TEST CONDITIONS	T <sub>A</sub> = 25°C	1A - 65 C	1A - 125 C	ONII
	+36 V Single Supply <sup>(1)</sup>	330	220	120	mA
	±15 V Dual Supply	330	220	120	mA
RUM (WQFN)	+12 V Single Supply	260	180	110	mA
	±5 V Dual Supply	240	160	100	mA
	+5 V Single Supply	180	120	80	mA

- Specified for nominal supply voltage only. (1)
- Refer to the total power dissipation (Ptot) limits in the Absolute Maximum Ratings table, which must be followed with the maximum continuous current specification.



## 6.6 ±15 V Dual Supply: Electrical Characteristics

 $V_{DD} = +15 \text{ V} \pm 10\%, \ V_{SS} = -15 \text{ V} \pm 10\%, \ \text{GND} = 0 \text{ V} \ \text{(unless otherwise noted)}$  Typical at  $V_{DD} = +15 \text{ V}, \ V_{SS} = -15 \text{ V}, \ T_A = 25^{\circ}\text{C} \ \text{(unless otherwise noted)}$ 

<b>J</b> 1	$V_{DD} = +15 \text{ V}, V_{SS} = -15 \text{ V}, I_A = $ PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT
ANALOG	SWITCH				-		
		V <sub>S</sub> = -10 V to +10 V	25°C		2	2.7	Ω
R <sub>ON</sub>	On-resistance	$I_D = -10 \text{ mA}$	-40°C to +85°C			3.4	Ω
		Refer to On-Resistance	-40°C to +125°C			4	Ω
		V <sub>S</sub> = -10 V to +10 V	25°C		0.1	0.18	Ω
$\Delta R_{ON}$	On-resistance mismatch between channels	$I_{D} = -10 \text{ mA}$	-40°C to +85°C			0.19	Ω
	Charmers	Refer to On-Resistance	-40°C to +125°C			0.21	Ω
		V <sub>S</sub> = -10 V to +10 V	25°C		0.2	0.46	Ω
R <sub>ON FLAT</sub>	On-resistance flatness	$I_S = -10 \text{ mA}$	-40°C to +85°C			0.65	Ω
		Refer to On-Resistance	-40°C to +125°C			0.7	Ω
R <sub>ON DRIFT</sub>	On-resistance drift	V <sub>S</sub> = 0 V, I <sub>S</sub> = -10 mA Refer to On-Resistance	-40°C to +125°C		0.008		Ω/°C
		V <sub>DD</sub> = 16.5 V, V <sub>SS</sub> = -16.5 V	25°C	3.4  4  0.1 0.18  0.19  0.21  0.2 0.46  0.65  0.7  0.008  -0.35 0.05 0.35  -3 3  -20 20  -0.6 0.1 0.6  -7 7  -45 45  -0.5 0.05 0.5  -3.5 3.5  -25 25  1.3 36  0 0.8  0.4 2  -1.5 -0.005  3.5  45 60  70  85	nA		
lovores	Source off leakage current <sup>(1)</sup>	Switch state is off $V_S = +10 \text{ V} / -10 \text{ V}$	-40°C to +85°C	-3		3	nA
I <sub>S(OFF)</sub>	Source on leakage current	V <sub>D</sub> = -10 V / + 10 V Refer to Off-Leakage Current	-40°C to +125°C	-20		20	nA
	Drain off leakage current <sup>(1)</sup>	$V_{DD}$ = 16.5 V, $V_{SS}$ = -16.5 V Switch state is off $V_{S}$ = +10 V / -10 V $V_{D}$ = -10 V / + 10 V Refer to Off-Leakage Current	25°C	-0.6	0.1	0.6	nA
ı			-40°C to +85°C	-7		7	nA
I <sub>D(OFF)</sub>			-40°C to +125°C	-45		45	nA
		V <sub>DD</sub> = 16.5 V, V <sub>SS</sub> = -16.5 V	25°C	-0.5	0.05	0.5	nA
I <sub>S(ON)</sub>	Channel on leakage current <sup>(2)</sup>	Switch state is on V <sub>S</sub> = V <sub>D</sub> = ±10 V Refer to On-Leakage Current	-40°C to +85°C	-3.5		3.5	nA
I <sub>D(ON)</sub>			-40°C to +125°C	-25		25	nA
LOGIC IN	PUTS (SEL / EN pins)	-					
V <sub>IH</sub>	Logic voltage high		-40°C to +125°C	1.3		36	V
V <sub>IL</sub>	Logic voltage low		-40°C to +125°C	0		0.8	V
I <sub>IH</sub>	Input leakage current		-40°C to +125°C		0.4	2	μΑ
I <sub>IL</sub>	Input leakage current		-40°C to +125°C	-1.5	-0.005		μΑ
C <sub>IN</sub>	Logic input capacitance		-40°C to +125°C		3.5		pF
POWER S	SUPPLY						
			25°C		45	60	μΑ
$I_{DD}$	V <sub>DD</sub> supply current	$V_{DD}$ = 16.5 V, $V_{SS}$ = -16.5 V Logic inputs = 0 V, 5 V, or $V_{DD}$	-40°C to +85°C			70	μA
		20g.5 mpato 0 v, 0 v, or v DD	-40°C to +125°C			85	μA
			25°C		7	24	μA
I <sub>SS</sub>	V <sub>SS</sub> supply current	$V_{DD}$ = 16.5 V, $V_{SS}$ = -16.5 V Logic inputs = 0 V, 5 V, or $V_{DD}$	-40°C to +85°C			30	μA
			-40°C to +125°C			38	μA

When  $V_S$  is positive,  $V_D$  is negative, or when  $V_S$  is negative,  $V_D$  is positive. When  $V_S$  is at a voltage potential,  $V_D$  is floating, or when  $V_D$  is at a voltage potential,  $V_S$  is floating.



## 6.7 ±15 V Dual Supply: Switching Characteristics

 $V_{DD}$  = +15 V ± 10%,  $V_{SS}$  = -15 V ± 10%, GND = 0 V (unless otherwise noted) Typical at  $V_{DD}$  = +15 V,  $V_{SS}$  = -15 V,  $T_A$  = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT
		V <sub>S</sub> = 10 V	25°C		110	130	ns
t <sub>TRAN</sub>	Transition time from control input	$R_L = 300 \Omega, C_L = 35 pF$	-40°C to +85°C		110 130 160 180 95 120 135 145 145 125 160 175 190 27 5 5 0.17 0.18 0.18 720 30 -70 -50 -107 -93 40 -0.15	ns	
		Refer to Transition Time	-40°C to +125°C			180	ns
		V <sub>S</sub> = 10 V	25°C		95	120	ns
t <sub>ON</sub>	Turn-on time from control input	$R_L = 300 \Omega$ , $C_L = 35 pF$ Refer to Turn-on and Turn-off	-40°C to +85°C			135	ns
		Time	-40°C to +125°C			145	ns
		V <sub>S</sub> = 10 V	25°C		125	160	ns
t <sub>OFF</sub>	Turn-off time from control input	$R_L = 300 \Omega$ , $C_L = 35 pF$ Refer to Turn-on and Turn-off	-40°C to +85°C			175	ns
		Time	-40°C to +125°C			190	ns
		V <sub>S</sub> = 10 V,	25°C		27		ns
t <sub>BBM</sub>	Break-before-make time delay	$R_L = 300 \Omega, C_L = 35 pF$	-40°C to +85°C	5			ns
		Refer to Break-before-make Time	-40°C to +125°C	5			ns
		V <sub>DD</sub> rise time = 1 μs	25°C		0.17		ms
t <sub>ON (VDD)</sub>	Device turn on time (V <sub>DD</sub> to output)	$R_L = 300 \Omega, C_L = 35 pF$	-40°C to +85°C		0.18		ms
	(VDD to output)	Refer to Turn-on (VDD) Time	-40°C to +125°C		0.18		ms
t <sub>PD</sub>	Propagation delay	$R_L = 50 \Omega$ , $C_L = 5 pF$ Refer to Propagation Delay	25°C		720		ps
Q <sub>INJ</sub>	Charge injection	V <sub>S</sub> = 0 V, C <sub>L</sub> = 100 pF Refer to Charge Injection	25°C		30		рС
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 0 V$ , $f = 100 kHz$ Refer to Off Isolation	25°C		-70		dB
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 0 V$ , $f = 1 MHz$ Refer to Off Isolation	25°C		-50		dB
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 0 V$ , $f = 100 kHz$ Refer to Crosstalk	25°C		-107		dB
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 0 V$ , $f = 1 MHz$ Refer to Crosstalk	25°C		-93		dB
BW	–3dB Bandwidth	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 0 V$ Refer to Bandwidth	25°C		40		MHz
IL	Insertion loss	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 0 V$ , $f = 1 MHz$	25°C		-0.15		dB
ACPSRR	AC Power Supply Rejection Ratio	$V_{PP}$ = 0.62 V on $V_{DD}$ and $V_{SS}$ $R_L$ = 50 $\Omega$ , $C_L$ = 5 pF, f = 1 MHz Refer to ACPSRR	25°C		-68		dB
THD+N	Total Harmonic Distortion + Noise	$V_{PP}$ = 15 V, $V_{BIAS}$ = 0 V $R_L$ = 10 k $\Omega$ , $C_L$ = 5 pF, f = 20 Hz to 20 kHz Refer to THD + Noise	25°C		0.0006		%
C <sub>S(OFF)</sub>	Source off capacitance	V <sub>S</sub> = 0 V, f = 1 MHz	25°C		45		pF
C <sub>D(OFF)</sub>	Drain off capacitance	V <sub>S</sub> = 0 V, f = 1 MHz	25°C		55		pF
C <sub>S(ON),</sub> C <sub>D(ON)</sub>	On capacitance	V <sub>S</sub> = 0 V, f = 1 MHz	25°C		165		pF



## 6.8 36 V Single Supply: Electrical Characteristics

 $V_{DD} = +36 \text{ V} \pm 10\%, \ V_{SS} = 0 \text{ V}, \ \text{GND} = 0 \text{ V} \ \text{(unless otherwise noted)}$  Typical at  $V_{DD} = +36 \text{ V}, \ V_{SS} = 0 \text{ V}, \ T_A = 25^{\circ}\text{C} \ \text{(unless otherwise noted)}$ 

71	$\begin{array}{c} V_{DD} - +36 \text{ V}, V_{SS} - 0 \text{ V}, I_A - 2 \\ \hline \textbf{PARAMETER} \end{array}$	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
		V <sub>S</sub> = 0 V to 30 V	25°C		2.1	3.1	Ω
R <sub>ON</sub>	On-resistance	$I_D = -10 \text{ mA}$	-40°C to +85°C			3.5	Ω
		Refer to On-Resistance	-40°C to +125°C			4.4	Ω
		V <sub>S</sub> = 0 V to 30 V	25°C		0.1	0.18	Ω
$\Delta R_{ON}$	On-resistance mismatch between channels	I <sub>D</sub> = -10 mA	-40°C to +85°C			0.19	Ω
		Refer to On-Resistance	-40°C to +125°C			0.21	Ω
		V <sub>S</sub> = 0 V to 30 V	25°C		0.7	1.25	Ω
R <sub>ON FLAT</sub>	On-resistance flatness	$I_D = -10 \text{ mA}$	-40°C to +85°C			1.3	Ω
		Refer to On-Resistance	-40°C to +125°C			1.35	Ω
R <sub>ON DRIFT</sub>	On-resistance drift	V <sub>S</sub> = 18 V, I <sub>S</sub> = -10 mA Refer to On-Resistance	-40°C to +125°C		0.008		Ω/°C
		V <sub>DD</sub> = 39.6 V, V <sub>SS</sub> = 0 V	25°C	-0.25	0.05	0.25	nA
lovores	Source off leakage current <sup>(1)</sup>	Switch state is off V <sub>S</sub> = 30 V / 1 V	-40°C to +85°C	-5		5	nA
I <sub>S(OFF)</sub>	Source on leakage current	V <sub>D</sub> = 1 V / 30 V Refer to Off-Leakage Current	-40°C to +125°C	-39		39	nA
ΔRON CON-ICHAIN  RON FLAT ON-I  RON DRIFT ON-I  IS(OFF) SOU  ID(OFF) Drai  LOGIC INPUTS  VIH LOGI  VIL LOGI  IIH INPU  IIL INPU  CIN LOGI  POWER SUPP		$V_{DD}$ = 39.6 V, $V_{SS}$ = 0 V Switch state is off $V_{S}$ = 30 V / 1 V $V_{D}$ = 1 V / 30 V Refer to Off-Leakage Current	25°C	-0.6	0.12	0.6	nA
	Drain off leakage current <sup>(1)</sup>		-40°C to +85°C	-12		12	nA
	Drain on loakage current		-40°C to +125°C	-80		80	nA
		V <sub>DD</sub> = 39.6 V, V <sub>SS</sub> = 0 V	25°C	-0.25	0.05	0.25	nA
	Channel on leakage current <sup>(2)</sup>	Switch state is on $V_S = V_D = 30 \text{ V or } 1 \text{ V}$	-40°C to +85°C	-5		5	nA
RON FLAT ON  RON FLAT ON  RON DRIFT ON  IS(OFF) Dra  IS(ON) Characteristic Characteristics Characteristic Characteristics Characteristic Char		Refer to On-Leakage Current	-40°C to +125°C	-39		39	nA
LOGIC IN	PUTS (SEL / EN pins)						
V <sub>IH</sub>	Logic voltage high		-40°C to +125°C	1.3		44	V
	Logic voltage low		-40°C to +125°C	0		0.8	V
I <sub>IH</sub>	Input leakage current		-40°C to +125°C		1	2.75	μA
I <sub>IL</sub>	Input leakage current		-40°C to +125°C	-1.25	-0.005		μA
C <sub>IN</sub>	Logic input capacitance		-40°C to +125°C		3.5		pF
POWER S	BUPPLY						
			25°C		50	75	μA
$I_{DD}$	V <sub>DD</sub> supply current	$V_{DD}$ = 39.6 V, $V_{SS}$ = 0 V Logic inputs = 0 V, 5 V, or $V_{DD}$	-40°C to +85°C			85	μΑ
		J,,	-40°C to +125°C			100	μΑ

<sup>(1)</sup> When  $V_S$  is positive,  $V_D$  is negative, or when  $V_S$  is negative,  $V_D$  is positive.

When  $V_S$  is at a voltage potential,  $V_D$  is floating, or when  $V_D$  is at a voltage potential,  $V_S$  is floating.



## 6.9 36 V Single Supply: Switching Characteristics

 $V_{DD}$  = +36 V ± 10%,  $V_{SS}$  = 0 V, GND = 0 V (unless otherwise noted) Typical at  $V_{DD}$  = +36 V,  $V_{SS}$  = 0 V,  $T_A$  = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT	
		V <sub>S</sub> = 18 V	25°C		85	135	ns	
t <sub>TRAN</sub>	Transition time from control input	$R_L = 300 \Omega, C_L = 35 pF$	-40°C to +85°C			150	ns	
		Refer to Transition Time	-40°C to +125°C			170	ns	
		V <sub>S</sub> = 18 V	25°C		90	130	ns	
ON	Turn-on time from control input	$R_L = 300 \Omega$ , $C_L = 35 pF$ Refer to Turn-on and Turn-off	-40°C to +85°C			150	ns	
		Time	-40°C to +125°C			170	ns	
		V <sub>S</sub> = 18 V	25°C		120	165	ns	
OFF	Turn-off time from control input	$R_L = 300 \Omega$ , $C_L = 35 pF$ Refer to Turn-on and Turn-off	-40°C to +85°C			180	ns	
		Time	-40°C to +125°C		195			
		V <sub>S</sub> = 18 V,	25°C		30		ns	
ВВМ	Break-before-make time delay	$R_L = 300 \Omega, C_L = 35 pF$	-40°C to +85°C	8			ns	
		Refer to Break-before-make Time	-40°C to +125°C	8	150			
		V <sub>DD</sub> rise time = 1 μs	25°C		0.16		ms	
ON (VDD)	Device turn on time (V <sub>DD</sub> to output)	$R_L = 300 \Omega, C_L = 35 pF$	-40°C to +85°C		0.17		ms	
	(VDD to output)	Refer to Turn-on (VDD) Time	-40°C to +125°C		0.17		ms	
i <sub>PD</sub>	Propagation delay	$R_L = 50 \Omega$ , $C_L = 5 pF$ Refer to Propagation Delay	25°C		900		ps	
Q <sub>INJ</sub>	Charge injection	V <sub>S</sub> = 18 V, C <sub>L</sub> = 100 pF Refer to Charge Injection	25°C		78		рС	
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 6 V$ , $f = 100 kHz$ Refer to Off Isolation	25°C		-70		dB	
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 6 V$ , $f = 1 MHz$ Refer to Off Isolation	25°C	-50			dB	
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 6 V$ , $f = 100 kHz$ Refer to Crosstalk	25°C		-112		dB	
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 6 V$ , $f = 1 MHz$ Refer to Crosstalk	25°C		-93		dB	
BW	–3dB Bandwidth	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 6 V$ Refer to Bandwidth	25°C		35		MHz	
L	Insertion loss	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 6 V$ , $f = 1 MHz$	25°C		-0.16		dB	
ACPSRR	AC Power Supply Rejection Ratio	$V_{PP}$ = 0.62 V on $V_{DD}$ and $V_{SS}$ $R_L$ = 50 $\Omega$ , $C_L$ = 5 pF, f = 1 MHz Refer to ACPSRR	25°C	-65			dB	
ΓHD+N	Total Harmonic Distortion + Noise	$V_{PP} = 18 \text{ V}, V_{BIAS} = 6 \text{ V}$ $R_{L} = 10 \text{ k}\Omega$ , $C_{L} = 5 \text{ pF}$ , $f = 20 \text{ Hz}$ to 20 kHz Refer to THD + Noise			%			
C <sub>S(OFF)</sub>	Source off capacitance	V <sub>S</sub> = 6 V, f = 1 MHz	25°C		45		pF	
C <sub>D(OFF)</sub>	Drain off capacitance	V <sub>S</sub> = 6 V, f = 1 MHz	25°C		60		pF	
C <sub>S(ON),</sub> C <sub>D(ON)</sub>	On capacitance	V <sub>S</sub> = 6 V, f = 1 MHz	25°C		165		pF	



## 6.10 12 V Single Supply: Electrical Characteristics

 $V_{DD} = +12 \text{ V} \pm 10\%, \ V_{SS} = 0 \text{ V}, \ \text{GND} = 0 \text{ V} \ \text{(unless otherwise noted)}$   $\text{Typical at V}_{DD} = +12 \text{ V}, \ V_{SS} = 0 \text{ V}, \ T_{A} = 25^{\circ}\text{C} \ \text{(unless otherwise noted)}$ 

•	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
		V <sub>S</sub> = 0 V to 10 V	25°C		2.8	5.4	Ω
R <sub>ON</sub>	On-resistance	$I_{D} = -10 \text{ mA}$	-40°C to +85°C			6.8	Ω
		Refer to On-Resistance	-40°C to +125°C			7.4	Ω
		V <sub>S</sub> = 0 V to 10 V	25°C		0.13	0.21	Ω
$\Delta R_{ON}$	On-resistance mismatch between channels	I <sub>D</sub> = -10 mA	-40°C to +85°C			0.23	Ω
	Chariners	Refer to On-Resistance	-40°C to +125°C			0.25	Ω
		V <sub>S</sub> = 0 V to 10 V	25°C		0.8	1.7	Ω
R <sub>ON FLAT</sub>	On-resistance flatness	$I_D = -10 \text{ mA}$	-40°C to +85°C			1.9	Ω
		Refer to On-Resistance	n-Resistance –40°C to +125°C			2	Ω
R <sub>ON DRIFT</sub>	On-resistance drift	V <sub>S</sub> = 0 V, I <sub>S</sub> = -10 mA Refer to On-Resistance	-40°C to +125°C		0.015		Ω/°C
		V <sub>DD</sub> = 13.2 V, V <sub>SS</sub> = 0 V	25°C	-0.25	0.01	0.25	nA
lovores	Source off leakage current <sup>(1)</sup>	Switch state is off V <sub>S</sub> = 10 V / 1 V	-40°C to +85°C	-2		2	nA
I <sub>S(OFF)</sub>	Source on lounage carroin	V <sub>D</sub> = 1 V / 10 V Refer to Off-Leakage Current	-40°C to +125°C	-16		16	nA
		V <sub>DD</sub> = 13.2 V, V <sub>SS</sub> = 0 V	25°C	-0.6	0.12	0.6	nA
I <sub>D(OFF)</sub>	Drain off leakage current <sup>(1)</sup>	Switch state is off $V_S = 10 \text{ V} / 1 \text{ V}$ $-40^{\circ}\text{C to } +85^{\circ}\text{C}$		-5		5	nA
·D(OFF)		V <sub>D</sub> = 1 V / 10 V Refer to Off-Leakage Current	-40°C to +125°C	-34		34	nA
		V <sub>DD</sub> = 13.2 V, V <sub>SS</sub> = 0 V	25°C	-0.35	0.01	0.35	nA
I <sub>S(ON)</sub>	Channel on leakage current <sup>(2)</sup>	Switch state is on V <sub>S</sub> = V <sub>D</sub> = 10 V or 1 V	-40°C to +85°C	-2		2	nA
$I_{D(ON)}$		Refer to On-Leakage Current	-40°C to +125°C	-16		16	nA
LOGIC IN	PUTS (SEL / EN pins)						
V <sub>IH</sub>	Logic voltage high		-40°C to +125°C	1.3		44	V
V <sub>IL</sub>	Logic voltage low		-40°C to +125°C	0		0.8	V
I <sub>IH</sub>	Input leakage current		-40°C to +125°C		0.4	2.25	μA
I <sub>IL</sub>	Input leakage current		-40°C to +125°C	-1.25	-0.005		μΑ
C <sub>IN</sub>	Logic input capacitance		-40°C to +125°C		3.5		pF
POWER S	SUPPLY					'	
		40.03/3/	25°C		30	44	μA
$I_{DD}$	V <sub>DD</sub> supply current	$V_{DD}$ = 13.2 V, $V_{SS}$ = 0 V Logic inputs = 0 V, 5 V, or $V_{DD}$	-40°C to +85°C			52	μA
		3,, 3	-40°C to +125°C			62	μA

When  $V_S$  is positive,  $V_D$  is negative, or when  $V_S$  is negative,  $V_D$  is positive. When  $V_S$  is at a voltage potential,  $V_D$  is floating, or when  $V_D$  is at a voltage potential,  $V_S$  is floating.



## 6.11 12 V Single Supply: Switching Characteristics

 $V_{DD}$  = +12 V ± 10%,  $V_{SS}$  = 0 V, GND = 0 V (unless otherwise noted) Typical at  $V_{DD}$  = +12 V,  $V_{SS}$  = 0 V,  $T_A$  = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT	
		V <sub>S</sub> = 8 V	25°C		100	180	ns	
t <sub>TRAN</sub>	Transition time from control input	$R_L = 300 \Omega, C_L = 35 pF$	-40°C to +85°C			220	ns	
		Refer to Transition Time	-40°C to +125°C		100 180 220 245 190 235 260 280 160 200 220 245 30 9 9 0.17 0.18 0.18 770 12 -70 -50 -112 -93			
		V <sub>S</sub> = 8 V	25°C			235	ns	
t <sub>ON</sub>	Turn-on time from control input	$R_L = 300 \Omega$ , $C_L = 35 pF$ Refer to Turn-on and Turn-off	–40°C to +85°C			260	ns	
		Time	–40°C to +125°C			280	ns	
		V <sub>S</sub> = 8 V	25°C		160	200 ns		
t <sub>OFF</sub>	Turn-off time from control input	$R_L = 300 \Omega$ , $C_L = 35 pF$ Refer to Turn-on and Turn-off	–40°C to +85°C			220	ns	
		Time	–40°C to +125°C			245	ns	
		V <sub>S</sub> = 8 V,	25°C		30		ns	
t <sub>BBM</sub>	Break-before-make time delay	$R_L = 300 \Omega, C_L = 35 pF$	–40°C to +85°C	9	220 ns 245 ns 190 235 ns 260 ns 280 ns 160 200 ns 220 ns 245 ns 30 ns 9 ns 0.17 ms 0.18 ms 0.18 ms 770 ps 12 pC -70 dB -50 dB -93 dB			
		Refer to Break-before-make Time	-40°C to +125°C	9				
		V <sub>DD</sub> rise time = 1 μs	25°C		0.17		ms	
t <sub>ON (VDD)</sub>	Device turn on time (V <sub>DD</sub> to output)	$R_L = 300 \Omega, C_L = 35 pF$	-40°C to +85°C		0.18		ms	
	( Tob to surpar)	Refer to Turn-on (VDD) Time	-40°C to +125°C		0.18		ms	
t <sub>PD</sub>	Propagation delay	$R_L = 50 \Omega$ , $C_L = 5 pF$ Refer to Propagation Delay	25°C		770		ps	
Q <sub>INJ</sub>	Charge injection	V <sub>S</sub> = 6 V, C <sub>L</sub> = 100 pF Refer to Charge Injection	25°C		12		рС	
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 6 V$ , $f = 100 kHz$ Refer to Off Isolation	25°C		-70		dB	
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 6 V$ , $f = 1 MHz$ Refer to Off Isolation	25°C		-50		dB	
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 6 V$ , $f = 100 kHz$ Refer to Crosstalk	25°C		-112		dB	
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 6 V$ , $f = 1 MHz$ Refer to Crosstalk	25°C		-93		dB	
BW	–3dB Bandwidth	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 6 V$ Refer to Bandwidth	25°C		50		MHz	
IL	Insertion loss	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 6 V$ , $f = 1 MHz$	25°C		-0.25		dB	
ACPSRR	AC Power Supply Rejection Ratio	$V_{PP}$ = 0.62 V on $V_{DD}$ and $V_{SS}$ $R_L$ = 50 $\Omega$ , $C_L$ = 5 pF, f = 1 MHz Refer to ACPSRR	25°C	<b>-70</b>			dB	
THD+N	Total Harmonic Distortion + Noise	$V_{PP}$ = 6 V, $V_{BIAS}$ = 6 V $R_L$ = 10 k $\Omega$ , $C_L$ = 5 pF, f = 20 Hz to 20 kHz Refer to THD + Noise	25°C		0.001		%	
C <sub>S(OFF)</sub>	Source off capacitance	V <sub>S</sub> = 6 V, f = 1 MHz	25°C		52		pF	
C <sub>D(OFF)</sub>	Drain off capacitance	V <sub>S</sub> = 6 V, f = 1 MHz	25°C		68		pF	
C <sub>S(ON)</sub> , C <sub>D(ON)</sub>	On capacitance	V <sub>S</sub> = 6 V, f = 1 MHz	25°C		170		pF	



## 6.12 ±5 V Dual Supply: Electrical Characteristics

 $V_{DD}$  = +5 V ± 10%,  $V_{SS}$  = -5 V ±10%, GND = 0 V (unless otherwise noted) Typical at  $V_{DD}$  = +5 V,  $V_{SS}$  = -5 V,  $T_A$  = 25°C (unless otherwise noted)

•	PARAMETER PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
		V <sub>S</sub> = -4.5 V to +4.5 V	25°C		3.3	6.3	Ω
R <sub>ON</sub>	On-resistance	$I_D = -10 \text{ mA}$	-40°C to +85°C			7.6	Ω
		Refer to On-Resistance	-40°C to +125°C			8.5	Ω
		V <sub>S</sub> = -4.5 V to +4.5 V	25°C		0.07	0.22	Ω
$\Delta R_{ON}$	On-resistance mismatch between channels	$I_D = -10 \text{ mA}$	-40°C to +85°C			0.23	Ω
	Chamilois	Refer to On-Resistance	-40°C to +125°C			0.25	Ω
		V <sub>S</sub> = -4.5 V to +4.5 V	25°C		1	2	Ω
R <sub>ON FLAT</sub>	On-resistance flatness	$I_D = -10 \text{ mA}$	-40°C to +85°C			2.1	Ω
		Refer to On-Resistance	-40°C to +125°C			2.2	Ω
R <sub>ON DRIFT</sub>	On-resistance drift	V <sub>S</sub> = 0 V, I <sub>S</sub> = -10 mA Refer to On-Resistance	-40°C to +125°C		0.015		Ω/°C
		V <sub>DD</sub> = +5.5 V, V <sub>SS</sub> = -5.5 V	25°C	-0.4	0.05	0.4	nA
lavores	Source off leakage current <sup>(1)</sup>	Switch state is off $V_S = +4.5 \text{ V} / -4.5 \text{ V}$	-40°C to +85°C	-2		2	nA
I <sub>S(OFF)</sub>	Course on leakage current	$V_D = -4.5 \text{ V} / + 4.5 \text{ V}$ Refer to Off-Leakage Current	-40°C to +125°C	-16	6 1 0.12 5	16	nA
		$V_{DD}$ = +5.5 V, $V_{SS}$ = -5.5 V	25°C	-1	0.12	1	nA
1	Drain off leakage current <sup>(1)</sup>	Switch state is off $V_S = +4.5 \text{ V} / -4.5 \text{ V}$	-40°C to +85°C	-5		5	nA
I <sub>D(OFF)</sub>	Drain on leakage current	V <sub>D</sub> = -4.5 V / + 4.5 V Refer to Off-Leakage Current	-40°C to +125°C	-35		35	nA
	Channel on leakage current <sup>(2)</sup>	V <sub>DD</sub> = +5.5 V, V <sub>SS</sub> = -5.5 V	25°C	-0.4	0.05	0.4	nA
I <sub>S(ON)</sub>		Switch state is on $V_S = V_D = \pm 4.5 \text{ V}$	-40°C to +85°C	-2		2	nA
I <sub>D(ON)</sub>		Refer to On-Leakage Current	-40°C to +125°C	-16		16	nA
LOGIC IN	PUTS (SEL / EN pins)					<u> </u>	
V <sub>IH</sub>	Logic voltage high		-40°C to +125°C	1.3		44	V
V <sub>IL</sub>	Logic voltage low		-40°C to +125°C	0		0.8	V
I <sub>IH</sub>	Input leakage current		-40°C to +125°C		0.4	2	μA
I <sub>IL</sub>	Input leakage current		-40°C to +125°C	-1.2	-0.005		μA
C <sub>IN</sub>	Logic input capacitance		-40°C to +125°C		3.5		pF
POWER S	SUPPLY		-			'	
			25°C		28	38	μΑ
$I_{DD}$	V <sub>DD</sub> supply current	$V_{DD}$ = +5.5 V, $V_{SS}$ = -5.5 V Logic inputs = 0 V, 5 V, or $V_{DD}$	-40°C to +85°C			44	μΑ
		25915 Hipato 6 V, 6 V, 51 V DD	-40°C to +125°C			55	μA
			25°C		6	8.4	μA
I <sub>SS</sub>	V <sub>SS</sub> supply current	$V_{DD}$ = +5.5 V, $V_{SS}$ = -5.5 V Logic inputs = 0 V, 5 V, or $V_{DD}$	-40°C to +85°C			11	μΑ
			-40°C to +125°C			20	μA

When  $V_S$  is positive,  $V_D$  is negative, or when  $V_S$  is negative,  $V_D$  is positive. When  $V_S$  is at a voltage potential,  $V_D$  is floating, or when  $V_D$  is at a voltage potential,  $V_S$  is floating.



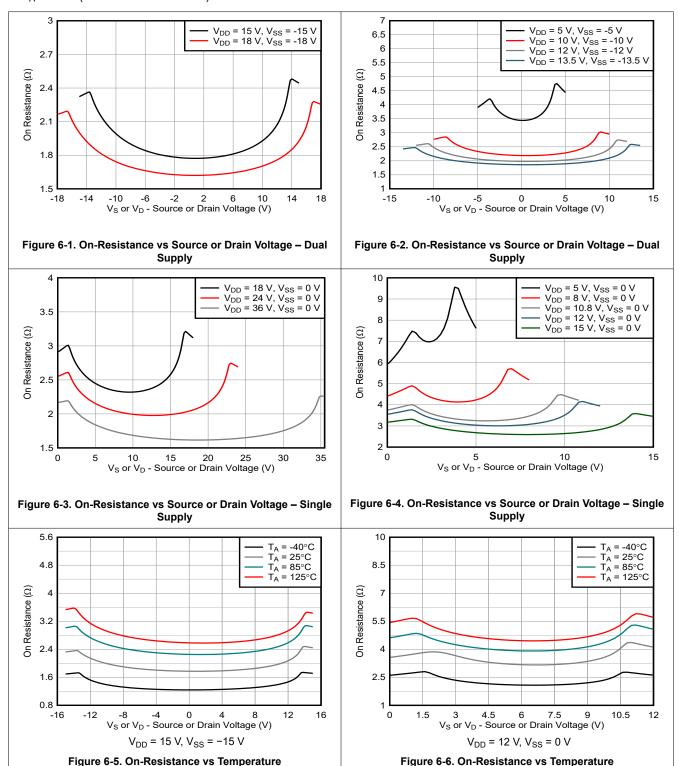
## 6.13 ±5 V Dual Supply: Switching Characteristics

 $V_{DD}$  = +5 V ± 10%,  $V_{SS}$  = -5 V ±10%, GND = 0 V (unless otherwise noted) Typical at  $V_{DD}$  = +5 V,  $V_{SS}$  = -5 V,  $T_A$  = 25°C (unless otherwise noted)

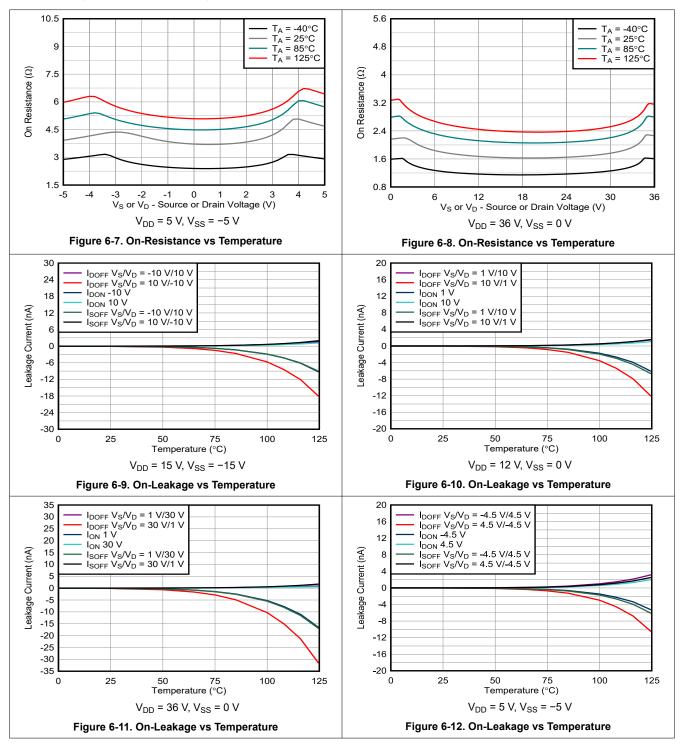
	PARAMETER	TEST CONDITIONS	T <sub>A</sub>	MIN	TYP	MAX	UNIT
		V <sub>S</sub> = 3 V	25°C		135	210	ns
t <sub>TRAN</sub>	Transition time from control input	$R_L = 300 \Omega, C_L = 35 pF$	-40°C to +85°C			250	ns
		Refer to Transition Time	-40°C to +125°C			285	ns
		V <sub>S</sub> = 3 V	25°C		140	290	ns
t <sub>ON</sub>	Turn-on time from control input	$R_L = 300 \Omega$ , $C_L = 35 pF$ Refer to Turn-on and Turn-off	-40°C to +85°C			315	ns
		Time	-40°C to +125°C			340	ns
		V <sub>S</sub> = 3 V	25°C		170	250	ns
t <sub>OFF</sub>	Turn-off time from control input	$R_L = 300 \Omega$ , $C_L = 35 pF$ Refer to Turn-on and Turn-off	-40°C to +85°C			270	ns
		Time	-40°C to +125°C			295	ns
		V <sub>S</sub> = 3 V,	25°C		32		ns
ВВМ	Break-before-make time delay	$R_L = 300 \Omega, C_L = 35 pF$	-40°C to +85°C	7			ns
		Refer to Break-before-make Time	-40°C to +125°C	7			ns
		V <sub>DD</sub> rise time = 1 μs	25°C		0.17		ms
ON (VDD)	Device turn on time (V <sub>DD</sub> to output)	$R_L = 300 \Omega, C_L = 35 pF$	-40°C to +85°C		0.18		ms
	(100	Refer to Turn-on (VDD) Time	-40°C to +125°C		0.18		ms
t <sub>PD</sub>	Propagation delay	$R_L$ = 50 $\Omega$ , $C_L$ = 5 pF Refer to Propagation Delay	25°C		670		ps
Q <sub>INJ</sub>	Charge injection	V <sub>S</sub> = 0 V, C <sub>L</sub> = 100 pF Refer to Charge Injection	25°C		9		рС
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 0 V$ , $f = 100 kHz$ Refer to Off Isolation	25°C		-70		dB
O <sub>ISO</sub>	Off-isolation	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 0 V$ , $f = 1 MHz$ Refer to Off Isolation	25°C		-50		dB
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 0 V$ , $f = 100 kHz$ Refer to Crosstalk	25°C		-117		dB
X <sub>TALK</sub>	Crosstalk	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 0 V$ , $f = 1 MHz$ Refer to Crosstalk	25°C		-94		dB
BW	–3dB Bandwidth	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 0 V$ Refer to Bandwidth	25°C		55		MHz
l <sub>L</sub>	Insertion loss	$R_L = 50 \Omega$ , $C_L = 5 pF$ $V_S = 0 V$ , $f = 1 MHz$	25°C		-0.28		dB
ACPSRR	AC Power Supply Rejection Ratio	$V_{PP}$ = 0.62 V on $V_{DD}$ and $V_{SS}$ $R_L$ = 50 $\Omega$ , $C_L$ = 5 pF, f = 1 MHz Refer to ACPSRR	25°C	-70			dB
THD+N	Total Harmonic Distortion + Noise	$V_{PP}$ = 5 V, $V_{BIAS}$ = 0 V $R_L$ = 10 k $\Omega$ , $C_L$ = 5 pF, f = 20 Hz to 20 kHz Refer to THD + Noise	= 10 k $\Omega$ , $C_L$ = 5 pF, 0.001 Us to 20 kHz			%	
C <sub>S(OFF)</sub>	Source off capacitance	V <sub>S</sub> = 0 V, f = 1 MHz	25°C		54		pF
C <sub>D(OFF)</sub>	Drain off capacitance	V <sub>S</sub> = 0 V, f = 1 MHz	25°C		72		pF
C <sub>S(ON),</sub> C <sub>D(ON)</sub>	On capacitance	V <sub>S</sub> = 0 V, f = 1 MHz	25°C		170		pF



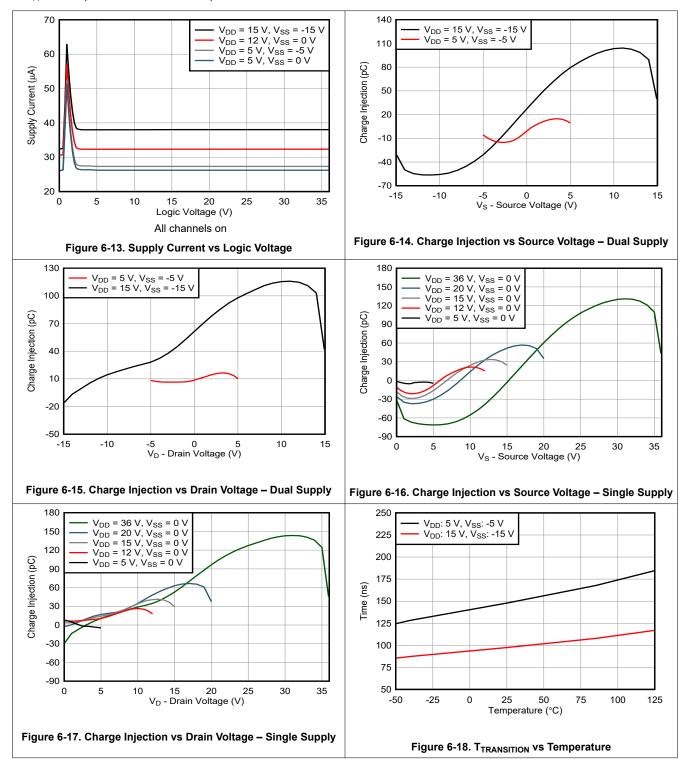
## **6.14 Typical Characteristics**



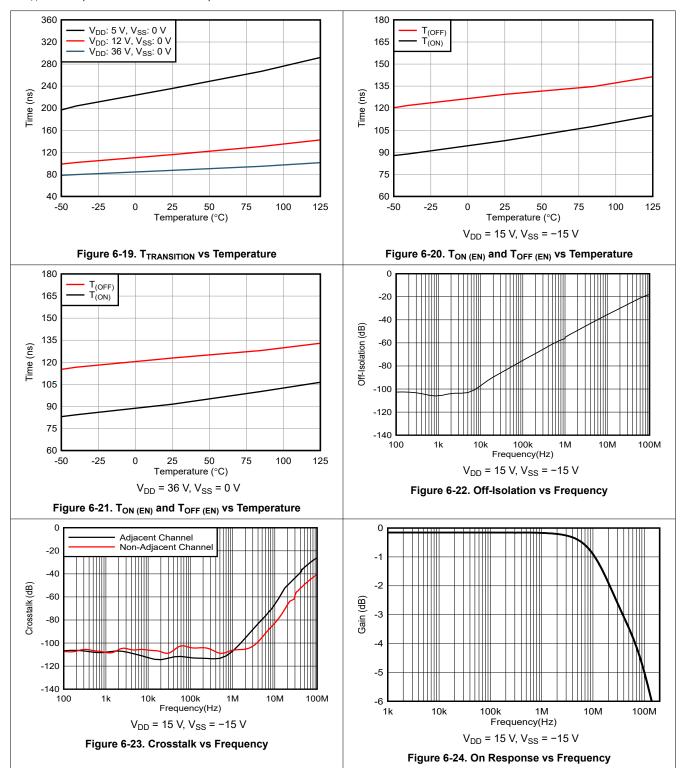














at T<sub>A</sub> = 25°C (unless otherwise noted)

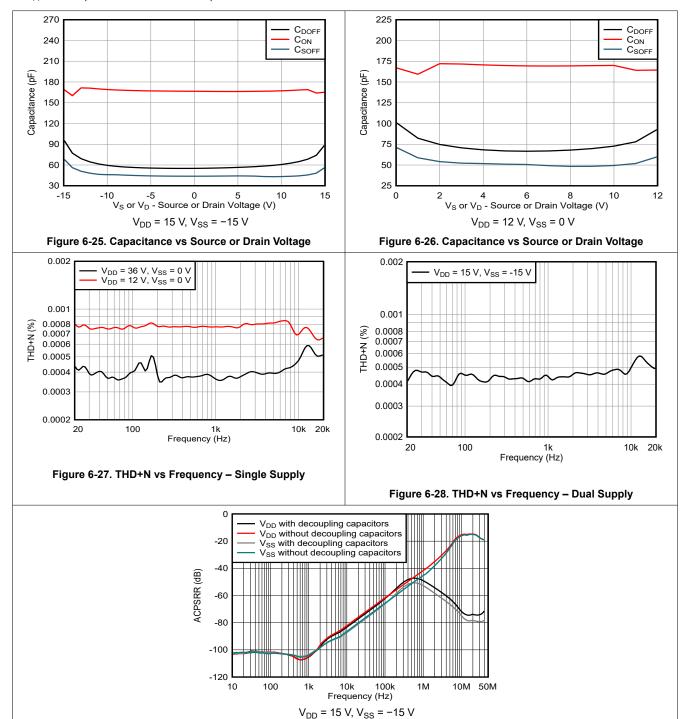


Figure 6-29. ACPSRR vs Frequency



#### 7 Parameter Measurement Information

#### 7.1 On-Resistance

The on-resistance of a device is the ohmic resistance between the source (Sx) and drain (D) pins of the device. The on-resistance varies with input voltage and supply voltage. The symbol  $R_{ON}$  is used to denote on-resistance. Figure 7-1 shows the measurement setup used to measure  $R_{ON}$ . Voltage (V) and current ( $I_{SD}$ ) are measured using this setup, and  $R_{ON}$  is computed with  $R_{ON} = V / I_{SD}$ .

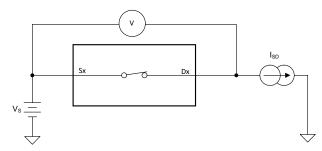


Figure 7-1. On-Resistance Measurement Setup

## 7.2 Off-Leakage Current

There are two types of leakage currents associated with a switch during the off state:

- · Source off-leakage current
- · Drain off-leakage current

Source leakage current is defined as the leakage current flowing into or out of the source pin when the switch is off. This current is denoted by the symbol  $I_{S(OFF)}$ .

Drain leakage current is defined as the leakage current flowing into or out of the drain pin when the switch is off. This current is denoted by the symbol  $I_{D(OFF)}$ .

Figure 7-2 shows the setup used to measure both off-leakage currents.

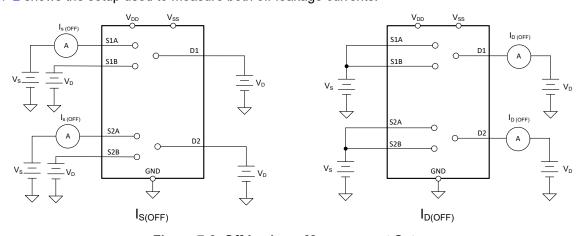


Figure 7-2. Off-Leakage Measurement Setup

#### 7.3 On-Leakage Current

Source on-leakage current is defined as the leakage current flowing into or out of the source pin when the switch is on. This current is denoted by the symbol  $I_{S(ON)}$ .

Drain on-leakage current is defined as the leakage current flowing into or out of the drain pin when the switch is on. This current is denoted by the symbol  $I_{D(ON)}$ .

Either the source pin or drain pin is left floating during the measurement. Figure 7-3 shows the circuit used for measuring the on-leakage current, denoted by  $I_{S(ON)}$  or  $I_{D(ON)}$ .

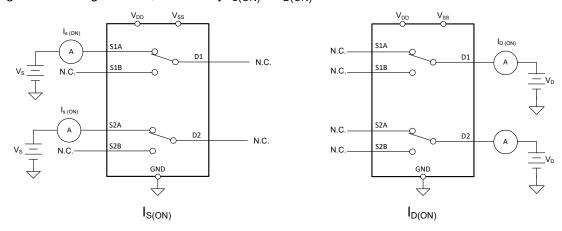


Figure 7-3. On-Leakage Measurement Setup

#### 7.4 Transition Time

Transition time is defined as the time taken by the output of the device to rise or fall 90% after the address signal has risen or fallen past the logic threshold. The 90% transition measurement is utilized to provide the timing of the device. System level timing can then account for the time constant added from the load resistance and load capacitance. Figure 7-4 shows the setup used to measure transition time, denoted by the symbol  $t_{TRANSITION}$ .

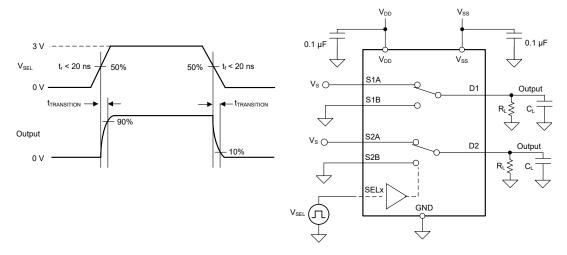


Figure 7-4. Transition-Time Measurement Setup

## 7.5 t<sub>ON(EN)</sub> and t<sub>OFF(EN)</sub>

Turn-on time is defined as the time taken by the output of the device to rise to 90% after the enable has risen past the logic threshold. The 90% measurement is utilized to provide the timing of the device. System level timing can then account for the time constant added from the load resistance and load capacitance. Figure 7-7 shows the setup used to measure turn-on time, denoted by the symbol  $t_{ON(EN)}$ .

Turn-off time is defined as the time taken by the output of the device to fall to 10% after the enable has fallen past the logic threshold. The 10% measurement is utilized to provide the timing of the device. System level timing can then account for the time constant added from the load resistance and load capacitance. Figure 7-7 shows the setup used to measure turn-off time, denoted by the symbol t<sub>OFF(FN)</sub>.

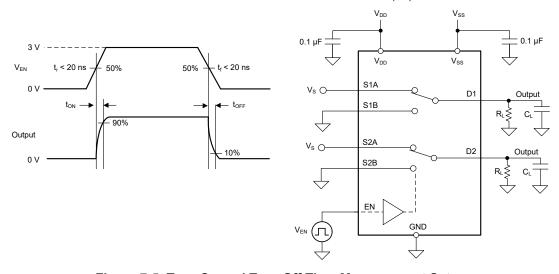


Figure 7-5. Turn-On and Turn-Off Time Measurement Setup

#### 7.6 Break-Before-Make

Break-before-make delay is a safety feature that prevents two inputs from connecting when the device is switching. The output first breaks from the on-state switch before making the connection with the next on-state switch. The time delay between the *break* and the *make* is known as break-before-make delay. Figure 7-6 shows the setup used to measure break-before-make delay, denoted by the symbol topen(BBM).

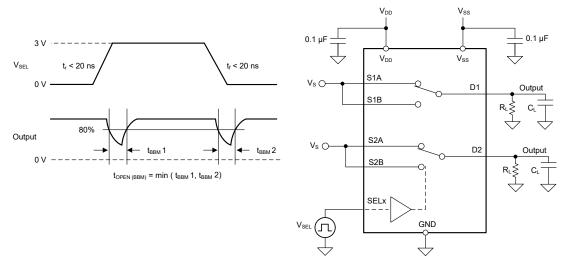


Figure 7-6. Break-Before-Make Delay Measurement Setup

## 7.7 t<sub>ON (VDD)</sub> Time

The  $t_{ON\ (VDD)}$  time is defined as the time taken by the output of the device to rise to 90% after the supply has risen past the supply threshold. The 90% measurement is used to provide the timing of the device turning on in the system. Figure 7-7 shows the setup used to measure turn on time, denoted by the symbol  $t_{ON\ (VDD)}$ .

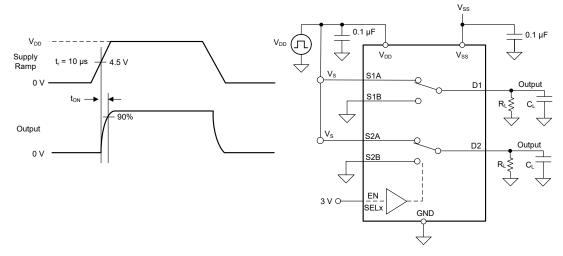


Figure 7-7. t<sub>ON (VDD)</sub> Time Measurement Setup

#### 7.8 Propagation Delay

Propagation delay is defined as the time taken by the output of the device to rise or fall 50% after the input signal has risen or fallen past the 50% threshold. Figure 7-8 shows the setup used to measure propagation delay, denoted by the symbol  $t_{PD}$ .

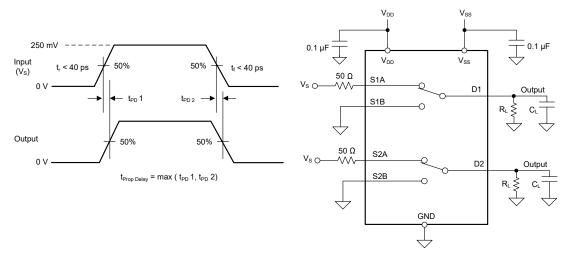


Figure 7-8. Propagation Delay Measurement Setup

#### 7.9 Charge Injection

The TMUX6236 has a transmission-gate topology. Any mismatch in capacitance between the NMOS and PMOS transistors results in a charge injected into the drain or source during the falling or rising edge of the gate signal. The amount of charge injected into the source or drain of the device is known as charge injection, and is denoted by the symbol Q<sub>INJ</sub>. Figure 7-9 shows the setup used to measure charge injection from source (Sx) to drain (D).

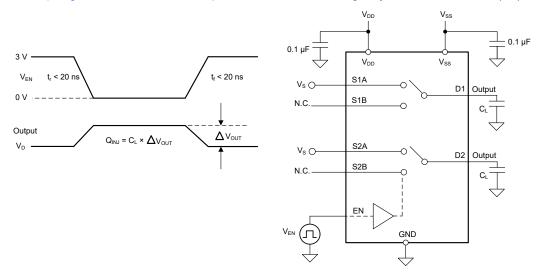


Figure 7-9. Charge-Injection Measurement Setup

#### 7.10 Off Isolation

Off isolation is defined as the ratio of the signal at the drain pin (D) of the device when a signal is applied to the source pin (Sx) of an off-channel. Figure 7-10 shows the setup used to measure, and the equation used to calculate off isolation.

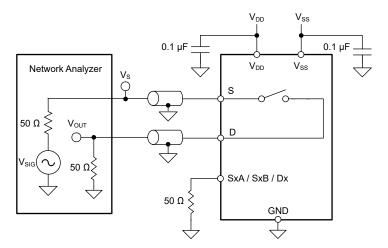


Figure 7-10. Off Isolation Measurement Setup

#### 7.11 Crosstalk

Crosstalk is defined as the ratio of the signal at the drain pin (D) of a different channel, when a signal is applied at the source pin (Sx) of an on-channel. Figure 7-11 shows the setup used to measure and the equation used to calculate crosstalk.

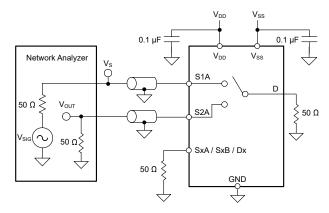


Figure 7-11. Crosstalk Measurement Setup

#### 7.12 Bandwidth

Bandwidth is defined as the range of frequencies that are attenuated by less than 3 dB when the input is applied to the source pin (Sx) of an on-channel, and the output is measured at the drain pin (D) of the device. Figure 7-12 shows the setup used to measure bandwidth.

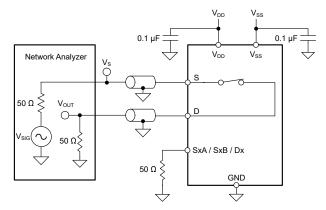


Figure 7-12. Bandwidth Measurement Setup

#### 7.13 THD + Noise

The total harmonic distortion (THD) of a signal is a measurement of the harmonic distortion, and is defined as the ratio of the sum of the powers of all harmonic components to the power of the fundamental frequency at the mux output. The on-resistance of the device varies with the amplitude of the input signal and results in distortion when the drain pin is connected to a low-impedance load. Total harmonic distortion plus noise is denoted as THD.

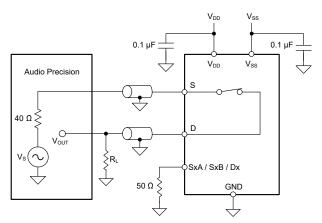


Figure 7-13. THD Measurement Setup

#### 7.14 Power Supply Rejection Ratio (PSRR)

PSRR measures the ability of a device to prevent noise and spurious signals that appear on the supply voltage pin from coupling to the output of the switch. The DC voltage on the device supply is modulated by a sine wave of 620 mVPP. The ratio of the amplitude of signal on the output to the amplitude of the modulated signal is the ACPSRR. A high ratio represents a high degree of tolerance to supply rail variation.

Figure 7-14 shows how the decoupling capacitors reduce high frequency noise on the supply pins. This helps stabilize the supply and immediately filter as much of the supply noise as possible.

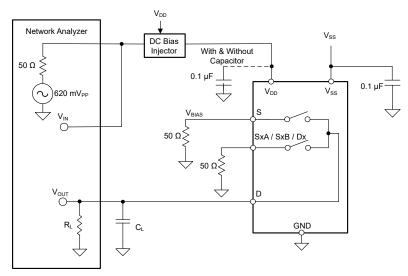
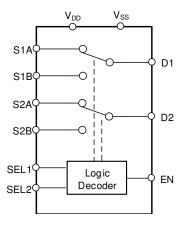


Figure 7-14. ACPSRR Measurement Setup

## 8 Detailed Description

## 8.1 Functional Block Diagram

The TMUX6236 is a 2:1, 2-channel multiplexer or demultiplexer. Each input is turned on or turned off based on the state of the select and enable pins.



#### 8.2 Feature Description

#### 8.2.1 Bidirectional Operation

The TMUX6236 conducts equally well from source (Sx) to drain (Dx) or from drain (Dx) to source (Sx). Each channel has very similar characteristics in both directions and supports both analog and digital signals.

### 8.2.2 Rail to Rail Operation

The valid signal path input or output voltage for TMUX6236 ranges from V<sub>SS</sub> to V<sub>DD</sub>.

#### 8.2.3 1.8 V Logic Compatible Inputs

The TMUX6236 has 1.8-V logic compatible control for all logic control inputs. 1.8-V logic level inputs allows the TMUX6236 to interface with processors that have lower logic I/O rails and eliminates the need for an external translator, which saves both space and bill of materials (BOM) cost. For more information on 1.8 V logic implementations, refer to Simplifying Design with 1.8 V logic Muxes and Switches.

#### 8.2.4 Integrated Pull-Down Resistor on Logic Pins

The TMUX6236 has internal weak pull-down resistors to GND to ensure the logic pins are not left floating. The value of this pull-down resistor is approximately 4  $M\Omega$ , but is clamped to about 1  $\mu$ A at higher voltages. This feature integrates up to three external components and reduces system size and cost.

#### 8.2.5 Fail-Safe Logic

The TMUX6236 supports Fail-Safe Logic on the control input pins (EN and SEL) allowing for operation up to 36 V above  $V_{SS}$ , regardless of the state of the supply pins. This feature allows voltages on the control pins to be applied before the supply pin, protecting the device from potential damage. Fail-Safe Logic minimizes system complexity by removing the need for power supply sequencing on the logic control pins. For example, the Fail-Safe Logic feature allows the logic input pins of the TMUX6236 to be ramped to +36 V while  $V_{DD}$  and  $V_{SS}$  = 0 V. The logic control inputs are protected against positive faults of up to +36 V in the powered-off condition, but does not offer protection against negative overvoltage conditions.

#### 8.2.6 Latch-Up Immune

Latch-up is a condition where a low impedance path is created between a supply pin and ground. This condition is caused by a trigger (current injection or overvoltage), but once activated, the low impedance path remains even after the trigger is no longer present. This low impedance path may cause system upset or catastrophic damage due to excessive current levels. The latch-up condition typically requires a power cycle to eliminate the low impedance path.

The TMUX6236 is constructed on silicon on insulator (SOI) based process where an oxide layer is added between the PMOS and NMOS transistor of each CMOS switch to prevent parasitic structures from forming. The oxide layer is also known as an insulating trench and prevents triggering of latch up events due to overvoltage or current injections. The latch-up immunity feature allows the TMUX6236 to be used in harsh environments. For more information on latch-up immunity refer to *Using Latch Up Immune Multiplexers to Help Improve System Reliability*.

#### 8.2.7 Ultra-Low Charge Injection

Figure 8-1 shows how the TMUX6236 device has a transmission gate topology. Any mismatch in the stray capacitance associated with the NMOS and PMOS causes an output level change whenever the switch is opened or closed.

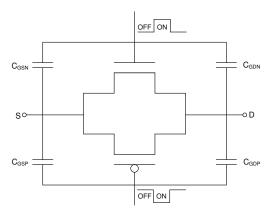


Figure 8-1. Transmission Gate Topology

The TMUX6236 contains specialized architecture to reduce charge injection on the Drain (Dx). To further reduce charge injection in a sensitive application, a compensation capacitor (Cp) can be added on the Source (Sx). This will ensure that excess charge from the switch transition will be pushed into the compensation capacitor on the Source (Sx) instead of the Drain (Dx). As a general rule, Cp should be 20x larger than the equivalent load capacitance on the Drain (Dx). Figure 8-2 shows charge injection variation with different compensation capacitors on the Source side. This plot was captured on the TMUX6219 as part of the TMUX62xx family with a 100 pF load capacitance.

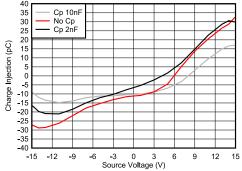


Figure 8-2. Charge Injection Compensation



#### 8.3 Device Functional Modes

When the EN pin of the TMUX6236 is pulled high, one of the switches is closed based on the state of the SEL pin. When the EN pin is pulled low, both of the switches are in an open state regardless of the state of the SEL pin. The control pins can be as high as 36 V.

#### 8.4 Truth Tables

Table 8-1 provides the truth tables for the TMUX6236.

Table 8-1. TMUX6236 Truth Table

EN	SELx	Selected Input Connected To Drain (D) Pin
0	X <sup>(1)</sup>	All channels are off (Hi-Z)
1	0	SxB
1	1	SxA

(1) X denotes do not care.

## 9 Application and Implementation

#### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

## 9.1 Application Information

The TMUX6236 is part of the precision switches and multiplexers family of devices. This device operates with dual supplies ( $\pm 4.5 \text{ V}$  to  $\pm 18 \text{ V}$ ), a single supply (4.5 V and 36 V), or asymmetric supplies (such as,  $V_{DD} = 5 \text{ V}$  and  $V_{SS} = -8 \text{ V}$ ), and offers rail-to-rail input and output. The TMUX6236 offers low  $R_{ON}$ , low on and off leakage currents and ultra-low charge injection performance. These features make the TMUX6236 a precision, robust, high-performance analog multiplexer for high-voltage, industrial applications.

#### 9.2 Typical Application

Differential reference signal switching is one application for the TMUX6236. AC reference signals are utilized in a variety of use cases as a stable reference in signal processing. Often times a differential signal is needed to reduce noise and keep signal integrity. To easily swap the direction and frequency of this reference signal, a 2:1, 2 channel precision multiplexer like the TMUX6236 can be used. Figure 9-1 shows a circuit example utilizing the TMUX6236 to control the AC reference signals. The switch can easily be configured for a differential signal on either X1 or X2. Additionally, if both SEL pins are low, then the output will be set to ground to ensure there is no active operation and reduce power consumption. The break-before-make feature allows transferring of a signal from one port to another, without shorting the inputs together. This device also offers low charge injection, which makes this device suitable for high precision systems.

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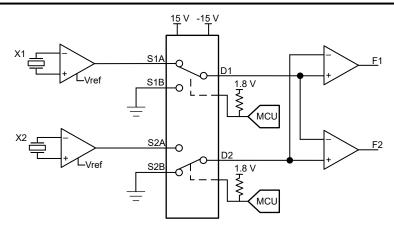


Figure 9-1. Differential Reference Switching

#### 9.2.1 Design Requirements

For this design example, use the parameters listed in Table 9-1.

Table 9-1. Design Parameters

PARAMETERS	VALUES				
Supply (V <sub>DD</sub> )	15 V				
Supply (V <sub>SS</sub> )	-15 V				
MUX I/O signal range	−15 V to 15 V (Rail-to-Rail)				
Control logic thresholds	1.8 V compatiable (up to V <sub>DD</sub> )				
EN	EN pulled high to enable the switch				

#### 9.2.2 Detailed Design Procedure

The TMUX6236 can operate without any external components except for the supply decoupling capacitors. All inputs passing through the switch must fall within the recommended operating conditions of the TMUX6236, including signal range and continuous current. The signal range for this design can be -15 V to +15 V and the maximum continuous current can be up to 330 mA for wide-range current measurement with a positive supply of 15 V on  $V_{DD}$  and negative supply of -15 V on  $V_{SS}$  (for more information, see Section 6.4). The TMUX6236 device are bidirectional, single-pole double-throw (SPDT) switches that offer low on-resistance, low leakage, and low power. These features make these devices suitable for precision and power sensitive applications.

#### 9.2.3 Application Curve

The low on-resistance of TMUX6236 and ultra-low charge injection performance make this device ideal for implementing high precision industrial systems. The TMUX6236 contains specialized architecture to reduce charge injection on the Drain side (D) (for more details, see Section 8.2.7). Figure 9-2 shows the plot for the charge injection versus source voltage for the TMUX6236.



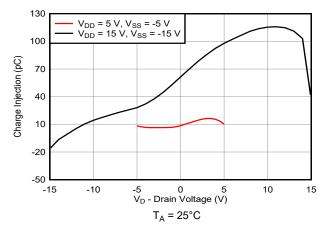


Figure 9-2. Charge Injection vs Drain Voltage

## 10 Power Supply Recommendations

The TMUX6236 operates across a wide supply range of  $\pm 4.5$  V to  $\pm 18$  V (4.5 V to 36 V in single-supply mode). The device also performs well with asymmetrical supplies such as  $V_{DD} = 12$  V and  $V_{SS} = -5$  V.

Power-supply bypassing improves noise margin and prevents switching noise propagation from the supply rails to other components. Good power-supply decoupling is important to achieve optimum performance. For improved supply noise immunity, use a supply decoupling capacitor ranging from 0.1  $\mu$ F to 10  $\mu$ F at both the  $V_{DD}$  and  $V_{SS}$  pins to ground. Place the bypass capacitors as close to the power supply pins of the device as possible using low-impedance connections. TI recommends using multi-layer ceramic chip capacitors (MLCCs) that offer low equivalent series resistance (ESR) and inductance (ESL) characteristics for power-supply decoupling purposes. For very sensitive systems or systems in harsh noise environments, avoiding the use of vias for connecting the capacitors to the device pins may offer superior noise immunity. The use of multiple vias in parallel lowers the overall inductance and is beneficial for connections to ground planes. Always ensure the ground (GND) connection is established before supplies are ramped.

## 11 Layout

## 11.1 Layout Guidelines

When a PCB trace turns a corner at a 90° angle, a reflection can occur. A reflection occurs primarily because of the change of width of the trace. At the apex of the turn, the trace width increases to 1.414 times the width. This increase upsets the transmission-line characteristics, especially the distributed capacitance and self–inductance of the trace which results in the reflection. Not all PCB traces can be straight and therefore some traces must turn corners. Figure 11-1 shows progressively better techniques of rounding corners. Only the last example (BEST) maintains constant trace width and minimizes reflections.

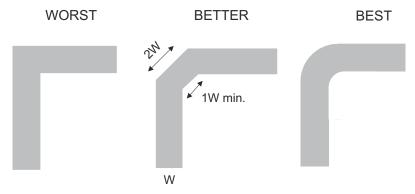


Figure 11-1. Trace Example

Route high-speed signals using a minimum of vias and corners which reduces signal reflections and impedance changes. When a via must be used, increase the clearance size around it to minimize its capacitance. Each via introduces discontinuities in the signal's transmission line and increases the chance of picking up interference from the other layers of the board. Be careful when designing test points; through-hole pins are not recommended at high frequencies.

#### Some key considerations are:

- For reliable operation, connect a decoupling capacitor ranging from 0.1 µF to 10 µF between VDD/VSS and GND. TI recommends a 0.1-µF and 1 µF capacitor, placing the lowest value capacitor as close to the pin as possible. Make sure that the capacitor voltage rating is sufficient for the supply voltage.
- · Keep the input lines as short as possible.
- Use a solid ground plane to help reduce electromagnetic interference (EMI) noise pickup.
- Do not run sensitive analog traces in parallel with digital traces. Avoid crossing digital and analog traces if
  possible, and only make perpendicular crossings when necessary.
- Using multiple vias in parallel will lower the overall inductance and is beneficial for connection to ground planes.

## 11.2 Layout Example

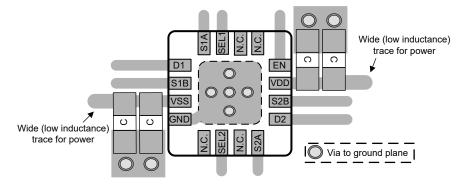


Figure 11-2. TMUX6236 Layout Example



## 12 Device and Documentation Support

### **12.1 Documentation Support**

#### 12.1.1 Related Documentation

For related documenation, see the following:

- Texas Instruments, Eliminate Power Sequencing with Powered-off Protection Signal Switches application brief
- · Texas Instruments, Improve Stability Issues with Low CON Multiplexers application brief
- Texas Instruments, QFN/SON PCB Attachment application report
- Texas Instruments, Quad Flatpack No-Lead Logic Packages application report
- Texas Instruments, Simplifying Design with 1.8 V logic Muxes and Switches application brief
- Texas Instruments, System-Level Protection for High-Voltage Analog Multiplexers application reports
- Texas Instruments, *True Differential, 4 x 2 MUX, Analog Front End, Simultaneous-Sampling ADC Circuit* circuit design

### 12.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### 12.3 Support Resources

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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#### 12.4 Trademarks

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#### 12.5 Glossary

This glossary lists and explains terms, acronyms, and definitions.

### 12.6 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

## 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
TMUX6236RUMR	ACTIVE	WQFN	RUM	16	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	TMUX T236	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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# **PACKAGE MATERIALS INFORMATION**

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### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

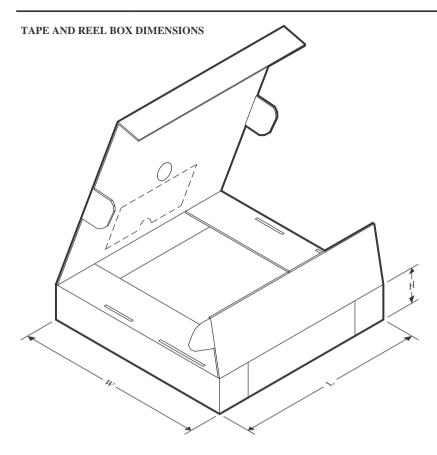


#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TMUX6236RUMR	WQFN	RUM	16	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 9-Sep-2022



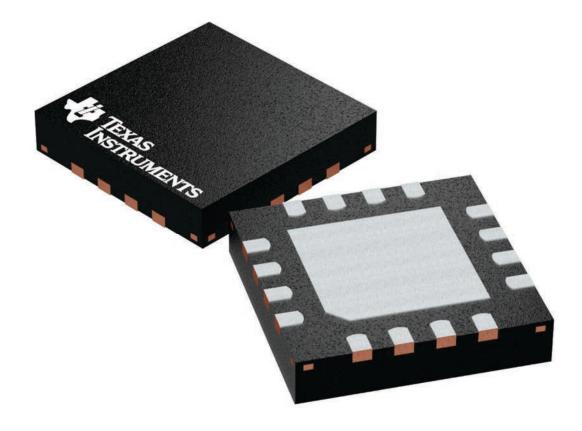
#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TMUX6236RUMR	WQFN	RUM	16	3000	367.0	367.0	35.0

4 x 4, 0.65 mm pitch

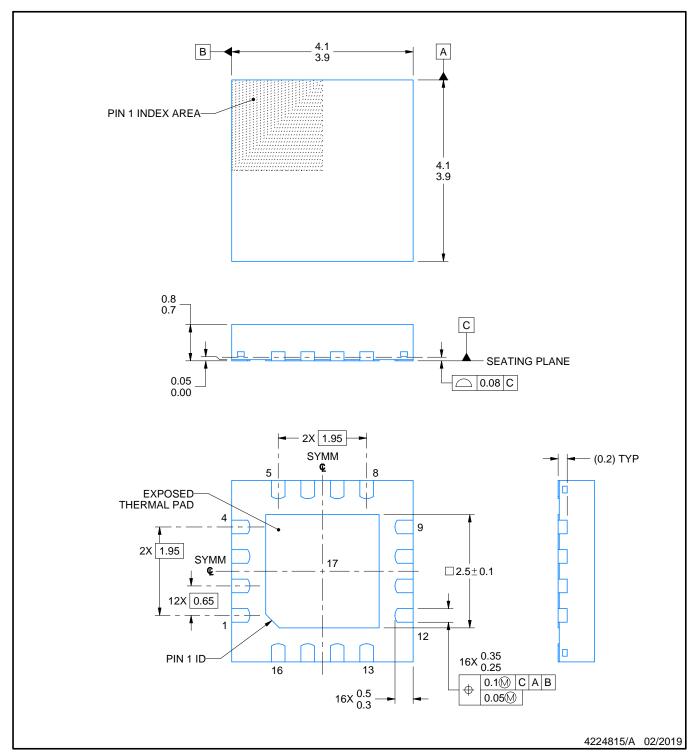
PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





PLASTIC QUAD FLATPACK - NO LEAD

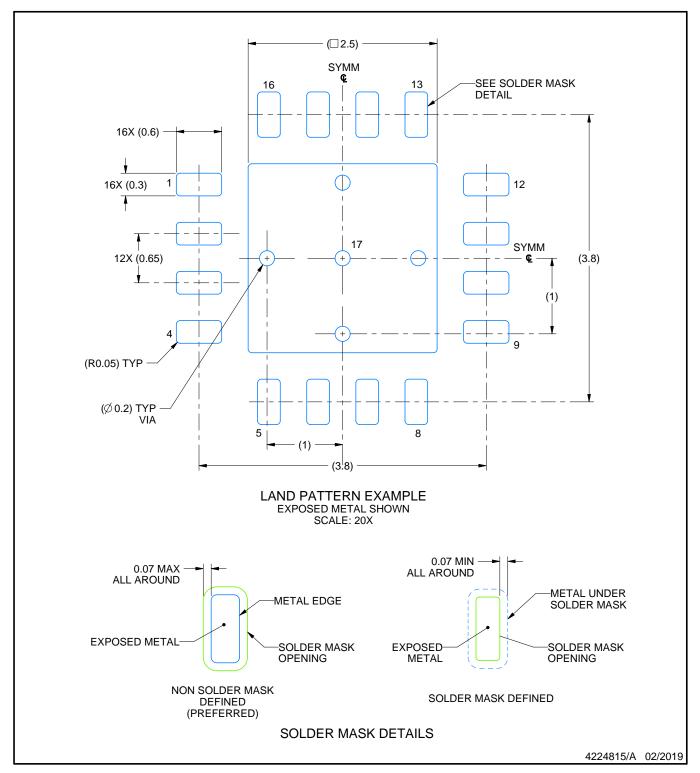


#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
  2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.



PLASTIC QUAD FLATPACK - NO LEAD

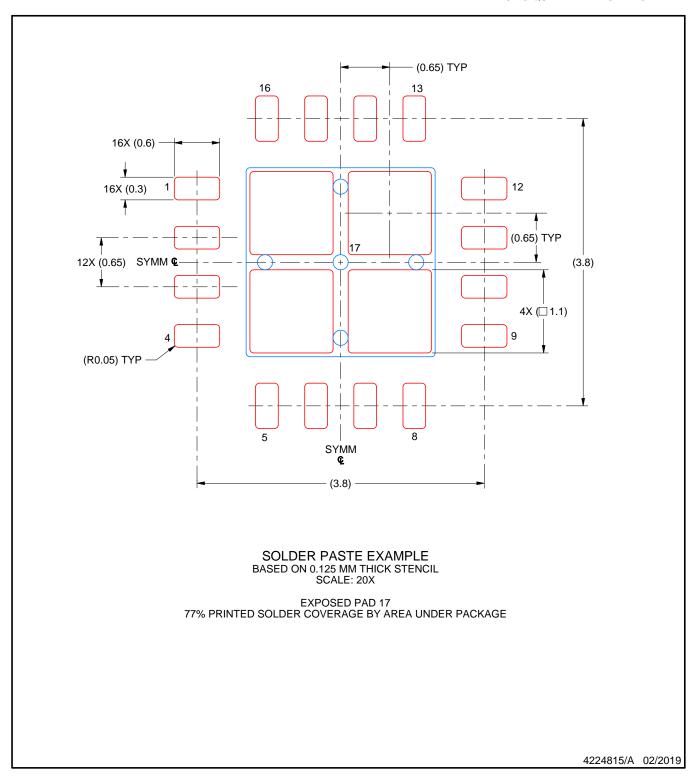


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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